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Substitute for form 14437-10	Application Number	10/599,227			
INFORMATION DISCLOSURE	Filing Date	09/22/2006			
	First Named Inventor	POWER, Joan F.			
STATEMENT BY APPLICANT	Art Unit				
(Use as many sheets as necessary)	Examiner Name				
Sheet 1 of 2	Attomey Docket Number	773/14555,3			

	U. S. PATENT DOCUMENTS						
Examiner Initials*	Cite No.1	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pegee, Columns, Lines, Where Relevant Passages or Relevan		
		Number-Kind Code ^{2 (F known)}			Figures Appear		
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STATEMENT BY APPLICANT		First Named Inventor	POWER, Joan F.			
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C		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
	C1	FU, S.W. et al., "Broadband Light Profile Microscopy: A Rapid and Direct Method for Thin Film Depth Imaging", :96-104	
	C2	POWER, Joan F. et al., "Longitudinal Light Profile Microscopy: A New Method for Seeing Below the Surfaces of", Applied Spectroscopy (1999) Vol. 53(12):1507-1519	
	СЗ	POWER, Joan F. et al., "Dual Beam Light Profile Microscopy: A New Technique for Optical", Applied Spectroscopy (2004) Vol. 58(2):166-178	
	C4	POWER, J.F., "Fresnel diffraction model for the point spread of a laser light profile microscope (LPM)", Appl. Phys. B 78 (2004), pp. 693-703	
	C5	SMITH, Warren J., Modern Optical Engineering: The Design of Optical Systems, Second Edition, 1990, pp. 270-278, McGraw-Hill, New York.	

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